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# **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	200			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	0.09		
Q <sub>g</sub> (Max.) (nC)	70			
Q <sub>gs</sub> (nC)	13			
Q <sub>gd</sub> (nC)	39			
Configuration	Single			

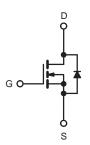
### **FEATURES**

- Surface Mount
- Low-Profile Through-Hole
- Available in Tape and ReelDynamic dV/dt Rating
- 150 °C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	200	V	
Gate-Source Voltage			$V_{GS}$	± 20		
Continuous Drain Current	V at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	I <sub>D</sub>	20		
	V <sub>GS</sub> at 10 V			13	Α	
Pulsed Drain Current <sup>a, e</sup>			I <sub>DM</sub>	72		
Linear Derating Factor			1.0	W/°C		
Single Pulse Avalanche Energy <sup>b, e</sup>		E <sub>AS</sub>	580	mJ		
Avalanche Current <sup>a</sup>			I <sub>AR</sub>	20	А	
Repetiitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	13	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	T <sub>C</sub> = 25 °C		3.1	W	
	T <sub>A</sub> =	: 25 °C	P <sub>D</sub>	130	- vv	
Peak Diode Recovery dV/dtc, e		dV/dt	5.0	V/ns		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>	7	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 2.7 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 18 A (see fig. 12).
- c.  $I_{SD} \le 20 \text{ A}$ ,  $dI/dt \le 150 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150 \,^{\circ}\text{C}$ .
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB Mounted, Steady-State) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	1.0		

### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	nless otherw	ise noted)		İ			1
PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, $I_D = 1 \text{ mA}^c$	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zeve Cata Valtaga Dvain Cuwant		V <sub>DS</sub> =	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V		-	25	- μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 160 V	V <sub>DS</sub> = 160 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A <sup>b</sup>	-	-	0.09	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 11 A <sup>d</sup>		6.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		1300	-	pF
Output Capacitance	C <sub>oss</sub>	]			430	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5 <sup>d</sup>		-	130	-	
Total Gate Charge	Qg			-	-	70	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 20 \text{ A}, V_{DS} = 160 \text{ V},$ see fig. 6 and $13^{b, c}$	-	-	13	
Gate-Drain Charge	Q <sub>gd</sub>	1	See fig. 6 and 16	-	-	39	
Turn-On Delay Time	t <sub>d(on)</sub>			-	14	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> -	= 100 V, I <sub>D</sub> = 20 A,	-	51	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_{\rm g} = 9.1 \ \Omega, R_{\rm D} = 5.4 \ \Omega, \text{ see fig. } 10^{\rm b, \ c}$		-	45	-	ns
Fall Time	t <sub>f</sub>			-	36	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	72	
Body Diode Voltage	$V_{SD}$	$T_J = 25 ^{\circ}\text{C},  I_S = 20  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 20 A, dl/dt = 100 A/μs <sup>b, c</sup>		-	300	610	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	3.4	7.1	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is			ninated b	y L <sub>S</sub> and	L <sub>D</sub> )

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.
- c. Uses IRF640/SiHF640 data and test conditions.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

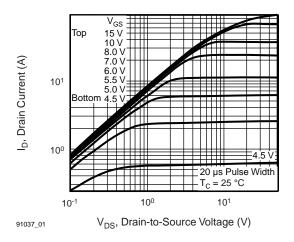


Fig. 1 - Typical Output Characteristics,  $T_J$  = 25 °C

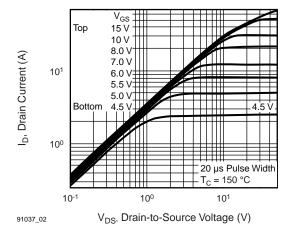


Fig. 2 - Typical Output Characteristics,  $T_J$  = 175 °C

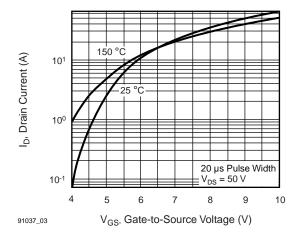


Fig. 3 - Typical Transfer Characteristics

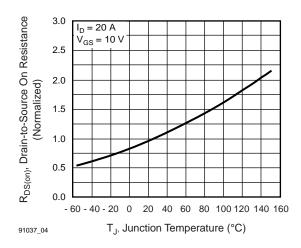


Fig. 4 - Normalized On-Resistance vs. Temperature



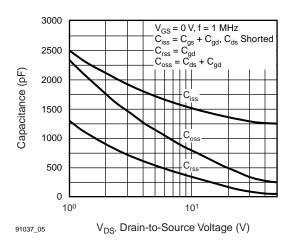


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

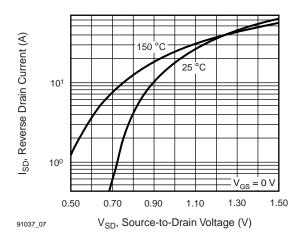


Fig. 7 - Typical Source-Drain Diode Forward Voltage

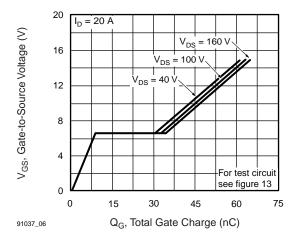


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

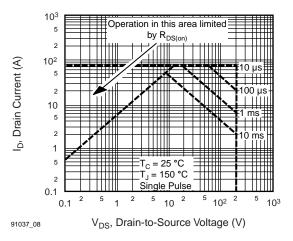


Fig. 8 - Maximum Safe Operating Area



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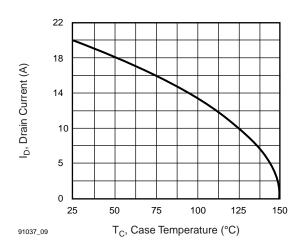


Fig. 9 - Maximum Drain Current vs. Case Temperature

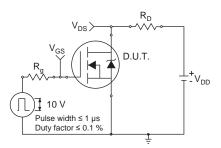


Fig. 10a - Switching Time Test Circuit

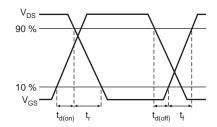


Fig. 10b - Switching Time Waveforms

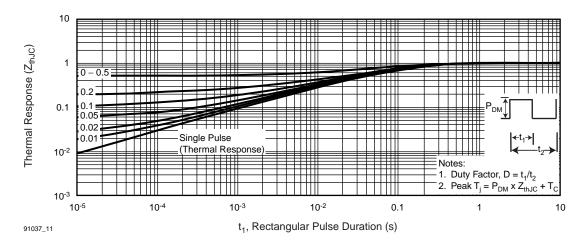


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



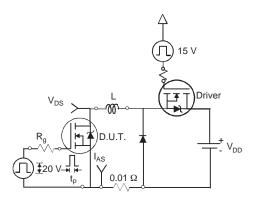


Fig. 12a - Unclamped Inductive Test Circuit

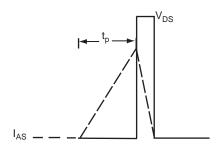


Fig. 12b - Unclamped Inductive Waveforms

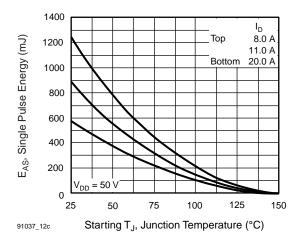


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

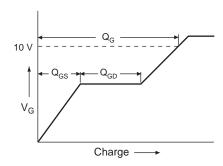


Fig. 13a - Basic Gate Charge Waveform

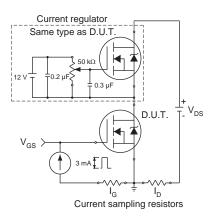
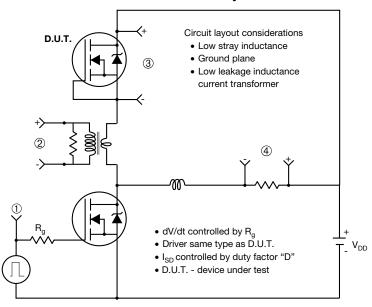


Fig. 13b - Gate Charge Test Circuit

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## Peak Diode Recovery dV/dt Test Circuit



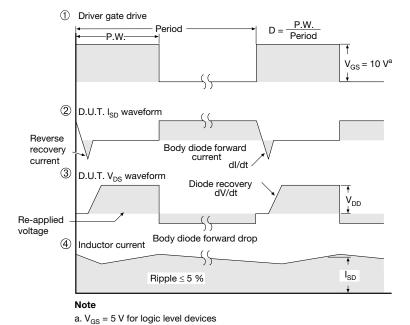


Fig. 14 - For N-Channel



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